

CLAIMS:

1. In an optical recording apparatus for writing information on an optical recording medium by a radiation beam, a method for setting a write parameter of the radiation beam at an optimum value, comprising

the step of writing at least one series of test patterns on the recording medium,

5 the test patterns having various values of the write parameter,

the step of reading the series of test patterns to form a read signal,

the step of deriving values of a read parameter from the read signal for each test pattern,

10 the step of determining the optimum value of the write parameter in dependence on the values of the read parameter,

characterised in that the values of the write parameter in subsequent test patterns form a symmetrical pattern.

2. The method according to Claim 1, wherein the symmetrical pattern has a triangular form.

15 3. The method according to Claim 1, wherein the method comprises the step of averaging parameter values derived from test patterns symmetrically located in a series.

4. The method according to Claim 1, wherein at least two series of test patterns are written on a disc-shaped recording medium, the series being substantially evenly distributed over one revolution of the recording medium, the values of the write parameter in
20 each of the at least two series lying within one predetermined range, and including the step of averaging parameter values derived from the at least two series.

5. The method according to Claim 4, wherein three series of test patterns are written.

6. The method according to Claim 4, wherein the averaging is performed on
25 the values of the read parameter.

7. The method according to Claim 4, wherein the averaging is performed on the values of the write parameter determined in dependence on the values of the read parameter.

8. An apparatus for writing information on an optical recording medium,
comprising

a radiation source for emitting a radiation beam,

a source control unit for controlling a write parameter of the radiation beam,

5 a test control unit for generating a series of test patterns for being written on the
recording medium, the test patterns having different values of the write parameter, an output of
the test control unit being connected to an input of the source control unit,

a read unit for reading test patterns and forming a corresponding read signal,

10 and a processor operatively connected for deriving values of a read parameter
from the read signal for each test pattern, for determining the optimum value of the write
parameter in dependence on the values of the read parameter and for forming a write control
signal representing the optimum value,

the write control signal being connected to an input of the source control unit,

15 characterised in that the values of the write parameter in subsequent test patterns
form a symmetrical pattern.

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